The Fault Hypothesis for the Time-Triggered Architecture

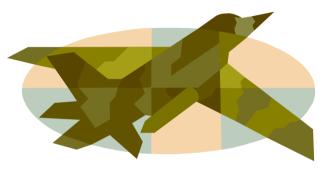
Hermann Kopetz TU Wien August 2004 1

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Outline

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- ♦ The Time-Triggered Architecture
- ♦ Contents of the Fault Hypothesis
- ♦ Fault Hypothesis of the TTA
- ♦ Transient Failures
- ♦ Design Faults
- ♦ Conclusion

Fly-by-wire Airplane: There is no mechanical or hydraulic connection between the pilot controls and the control surfaces.



Drive-by-wire Car: There is no mechanical or hydraulic connection between the steering wheel and the wheels.



The 10⁻⁹ Challenge

- Critical system services must be more reliable than any one of the components: e.g., System Dependability 1 FIT--Component dependability 1000 FIT (1 FIT: 1 failure in 10⁹ hours)
- Architecture must be distributed and support fault-tolerance to mask component failures.
- System as a whole is **not testable** to the required level of dependability.
- The safety argument is based on a combination of experimental evidence about the expected failure modes and failures rates of fault-containment regions (FCR) and a formal dependability model that depicts the system structure from the point of view of dependability.
- ◆ Independence of the FCRs is a critical issue.

The Time-Triggered Architecture (TTA)

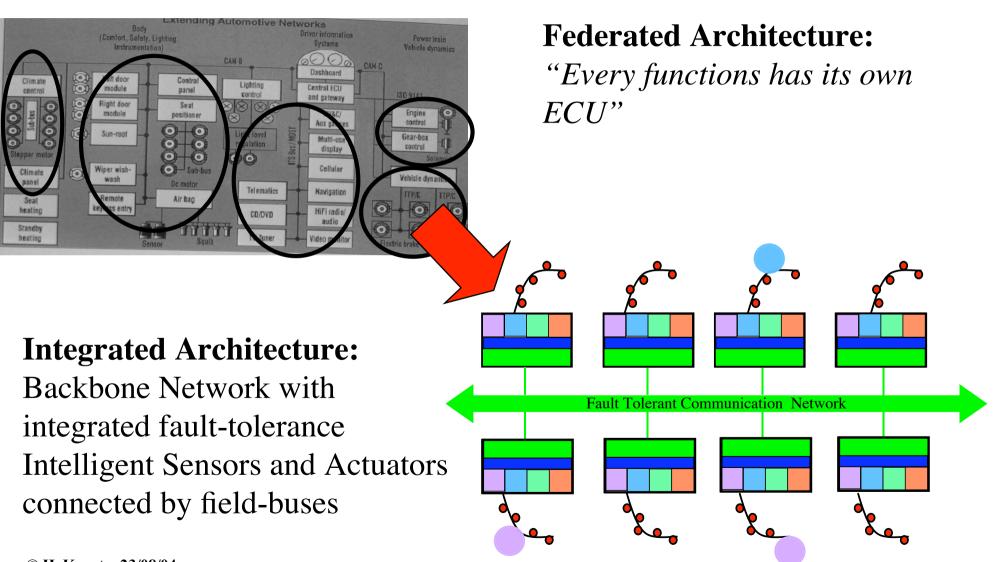
provides an execution environment for real-time applications. It is

- ♦ a *distributed architecture*, where a node can be a single chip computer (SoC).
- an *integrated architecture*, where different application subsystems (DAS) up to the *highest criticality class* can be integrated into a single framework.
- ♦ a *platform architecture* that provides technology invariant interfaces to the application software.
- ♦ a *generic architecture*, which can be deployed in different application domains (e.g., automotive, aerospace, train signaling, process control, mutimedia) where real-time performance is an issue.
- ◆ It provides a *fault-tolerant global time-base* of high precision at every node.

Kopetz, H, Bauer, G., The Time-Triggered Architecture, Proc. of the IEEE, Jan 2003, Vol 91 p. 112-126

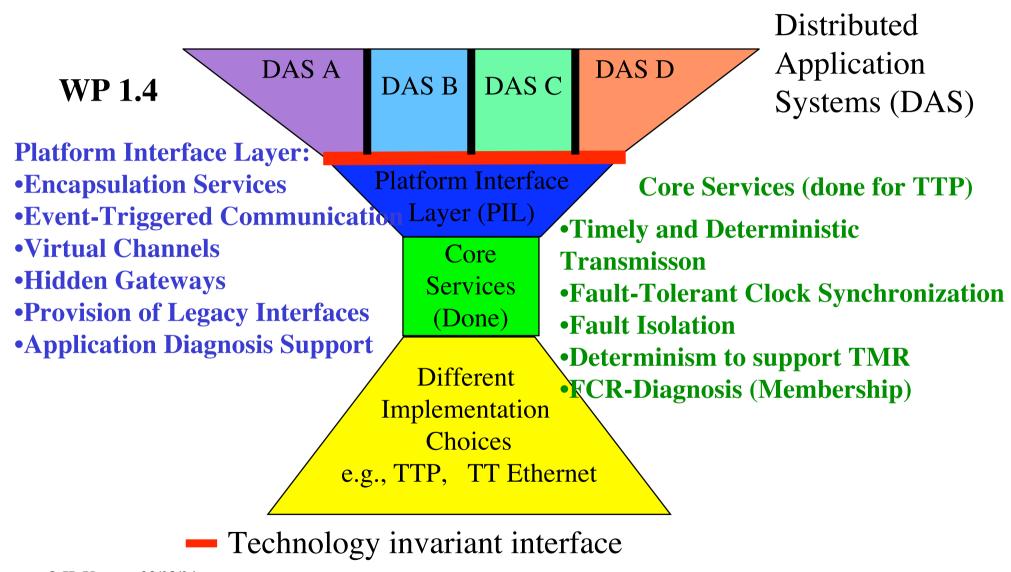
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From a Federated to an Integrated Architecture

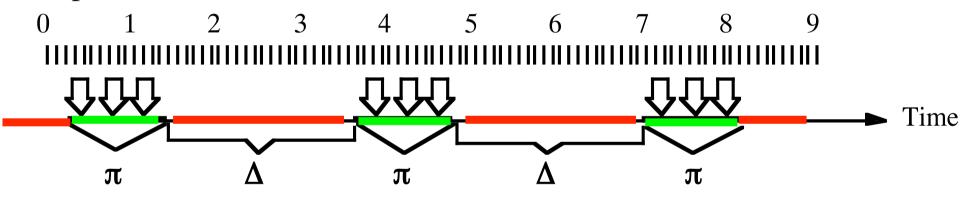


The ideal future avionics systems would combine the complexity management advantages of the federated approach, but would also realize the functional integration and hardware efficiency benefits of an integrated system. 7

Hammett Robert. *Flight Critical Electronics System Design*, IEEE AESS Systems Magazine, June 2003, p.32



If the occurrence of events is restricted to some active intervals with duration π with an interval of silence of duration Δ between any two active intervals, then we call the timebase π/Δ -sparse, or sparse for short.



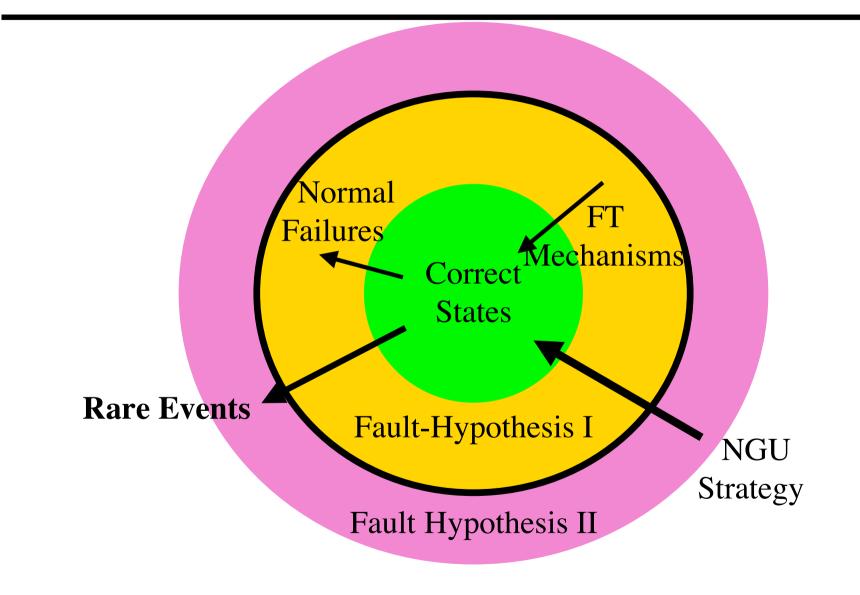
Events \mathbf{J} are only allowed to occur at subintervals of the timeline

In a sparse time base, instants can be represented by integers.

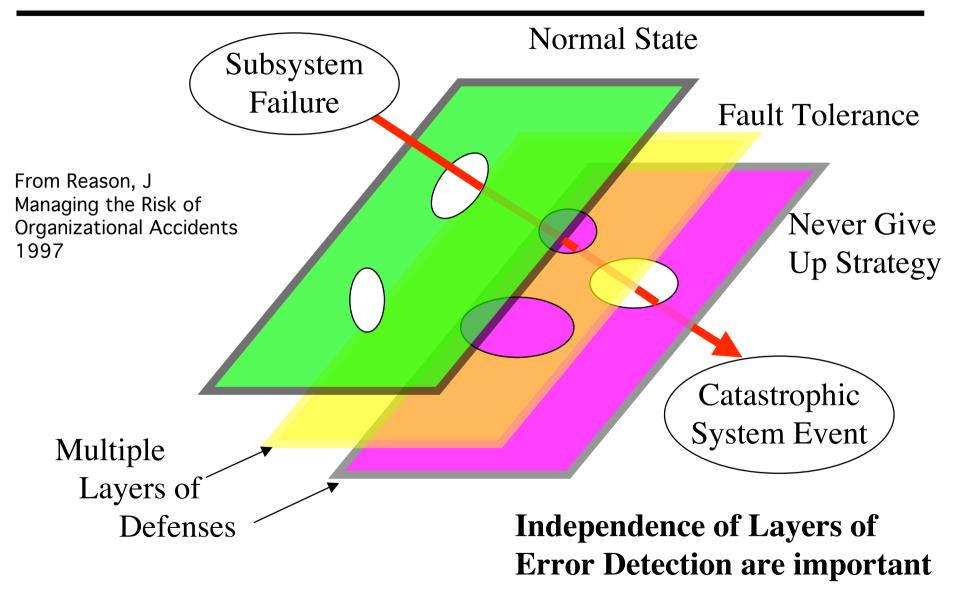
- The Fault-Hypothesis states the *assumptions* about the types and number of faults that a fault-tolerant system must tolerate.
- The assumption coverage states to what extent are these assumptions met by *reality*. The assumption coverage limits the dependability of a perfect fault-tolerant system.
- The fault hypothesis partitions the fault space into *covered* faults and *uncovered* faults.
- ♦ The fault hypothesis is the most important document in the design of a fault-tolerant system.

- **i. Design of the Fault-Tolerance Algorithms:** Without a precise fault-hypothesis it is not known which fault-classes must be addressed during the system design.
- **ii. Estimation of the Assumption Coverage:** Probability that the assumptions that are contained in the fault hypothesis are not met by reality.
- **iii. Validation and Certification**: For the validation it must be known which faults are supposed to be tolerated by the given system.
- **iv. Design of the Never-Give-Up (NGU) Strategy**: In case the fault hypothesis is violated the NGU process must be started.

System States of a FT System



Approach to Safety: The Swiss-Cheese Model



Fault Hypothesis I:

Specification of the faults that must be tolerated without any impact on essential system services.

Example: Arbitrary failure of an SoC

Fault Hypothesis II:

Specification of faults that can be handled in the rare-event scenario, e.g., for the never-give-up (NGU) strategy

Example: massive transients that causes the failure of all communication and more than one node during a limited interval of time

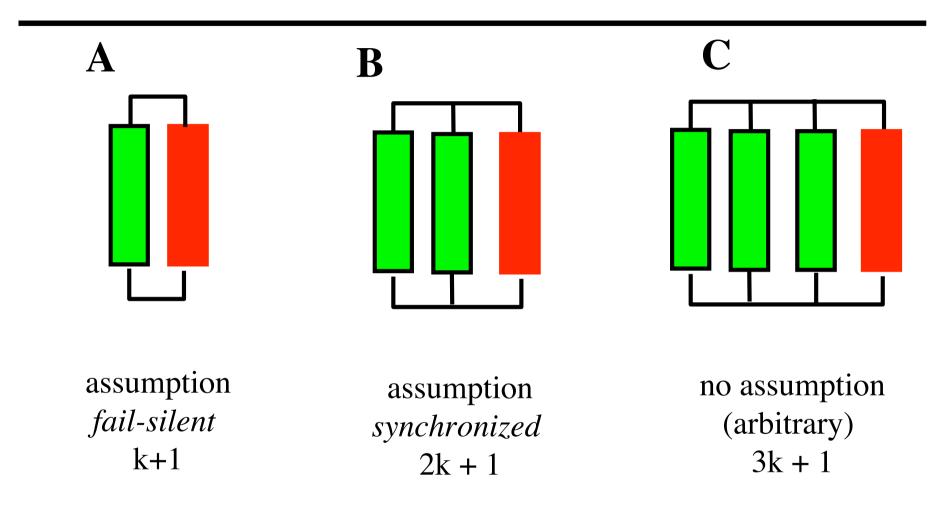
- **i.** Unit of Failure: What is the Fault-Containment Region (FCR)?
- **ii.** Failure Modes: What are the failure modes of the FCR?
- **iii. Frequency of Failures:** What is the assumed MTTF between failures for the different failure modes eg. transient failures vs permanent failures?
- **iv. Detection:** How are failures detected? How long is the detection latency?
- v. State Recovery: How long does it take to repair corrupted state (in case of a transient fault)?

Unit of Failure: Fault Containment Region (FCR)¹⁶

A *fault-containment region (FCR)* is a set of subsystems that shares one or more common resources that can be affected by a single fault and is assumed to fail **independently** from other FCRs.

- Tolerance w.r.t. *spatial proximity faults* requires spatial separation of FCRs: **distributed architectures** required.
- The fault hypothesis must specify the failure modes of the FCRs and their associated frequencies.
- Beware of shared resources that compromise the independence assumption: common hardware, power supply, oscillator, earthing, single timing source.

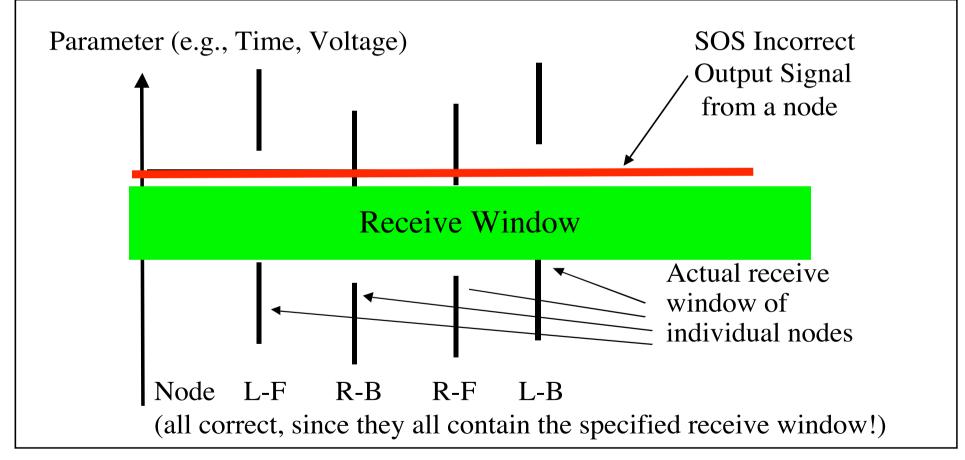
Failure Modes of an FCR--Are there Restrictions? ¹⁷



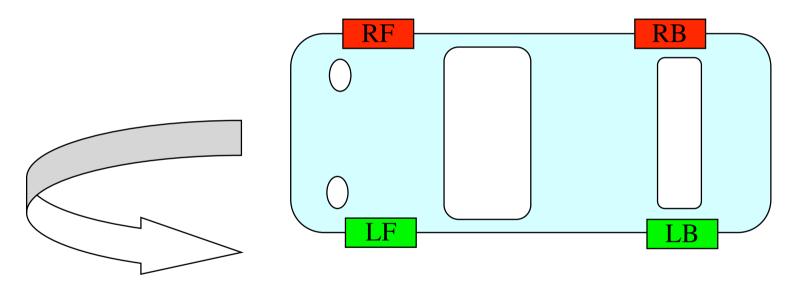
What is the *assumption coverage* in cases A and B?

Example: Slightly-out-of-Specification (SOS) Failure¹⁸

The following is an example for the type of asymmetric non-fail-silent failures that have been observed during experiments:



Consider the scenario where the right two brakes *do not* accept an SOS-faulty brake-command message, while the left two brakes *do* accept this message and brake.

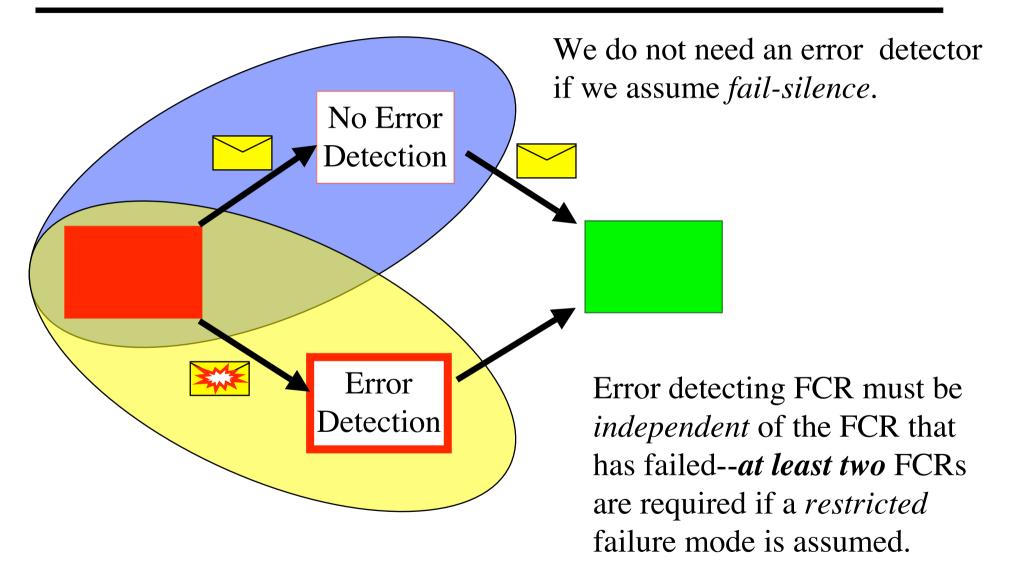


If the two left wheels brake, while the two right wheels do not brake, the car will turn. There are two basic mechanisms that compromise the independence of FCRs

- ♦ Missing fault isolation among the FCRs
- Error propagation--the consequences of a fault, the ensuing error, propagates to a healthy FCR by an erroneous message.

The independence of failures of different FCRs is the most critical issue in the design of an ultra-dependable system.

Fault Containment vs. Error Containment



Error Containment Region (ECR)

In a distributed computer system the consequences of a fault, the ensuing error, can propagate outside the originating FCR (Fault Containment Region) by an **erroneous message** of the faulty node to the environment.

- A propagated error **invalidates** the independence assumption.
- The error detector must be in a **different FCR** than the faulty unit.
- Distinguish between architecture-based and application-based error detection
- Distinguish between error detection in the time-domain and error detection in the value domain.

Consequences for an Architecture

In a safety-critical application an SoC (System on Chip) must be considered to form a *a single FCR (ie. a single unit of failure)* that can fail in an *arbitrary* failure mode because of:

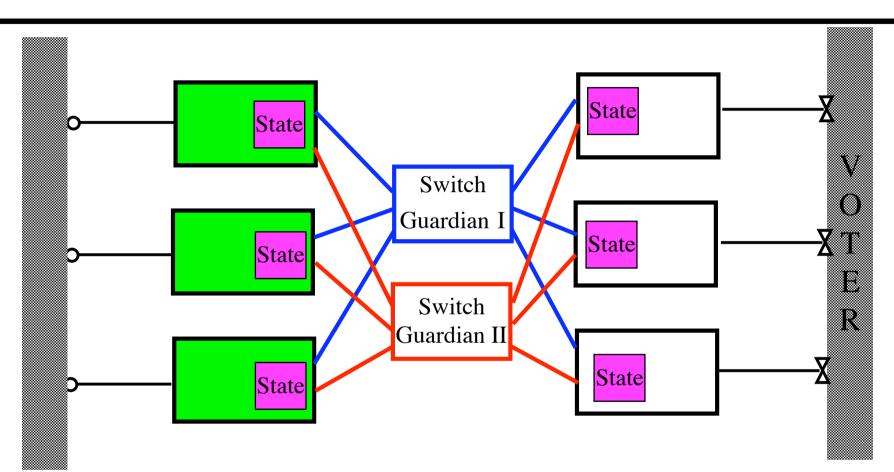
- ◆ Same Physical Space (Physical Proximity Failures)
- ♦ Same Wafer Production Process and Mask (Mask Alignment Issues)
- ♦ Same Bulk Material
- ♦ Same Power Supply and Same Earthing
- ♦ Same Timing Source

Although some of these dependencies can be eliminated, others cannot. We cannot assume an *independent* error detector on the same die.

Fault Hypothesis in the TTA w.r.t. Physical Faults ²⁴

- **i.** A Node Computer forms a single FCR that can fail in an arbitrary failure mode.
- **ii.** A communication channel including the central guardian forms a single FCR that can fail to distribute messages but cannot generate messages on its own.
- **iii.** A central guardian in the communication system transforms (SOS) failures to fail-silent failures in the temporal domain.
- **iv. Error detection** is performed by a membership and clique avoidance algorithms.
- **v. The system can recover** from a single failure within two TDMA rounds.

TMR Structure for Safety-Critical Tasks



State

In order to flush out *quasi-permanent state errors* caused by a transient fault, the state must be periodically subject to voting.

Assumption about the Frequency of Faults of SoCs:²⁶

Assumed Behavioral Hardware Failure Rates (Orders of Magnitude):

Type of Failure	Failure Rate in Fit	Source
Transient Node Failures (fail silent)	<1 000 000 Fit (MTTF > 1000 hours)	Neutron bombardment Aerospace
Transient Node Failure (non-fail silent)	<10 000 Fit (MTTF> 100 000)	Fault Injection Experiments
Permanent Hardware Failures	<100 Fit (MTTF> 10 000 000)	Automotive Field Data

Tendency: Increase of Transient Failures

Millions of fault injection experiments have been carried out in the PDCS, TTA and FIT project over a period of more than ten years to find out which are realistic assumptions:

- Software based (TU Vienna, Austria)
- ♦ Alpha Particle (Chalmers University, Sweden)
- ♦ VLSI-model based (Univ. of Valencia, Spain, Carinthia Tech, Austria)
- ♦ Pin Level (LAAS, Toulouse, France, Univ. of Valencia, Spain)

Conclusions:

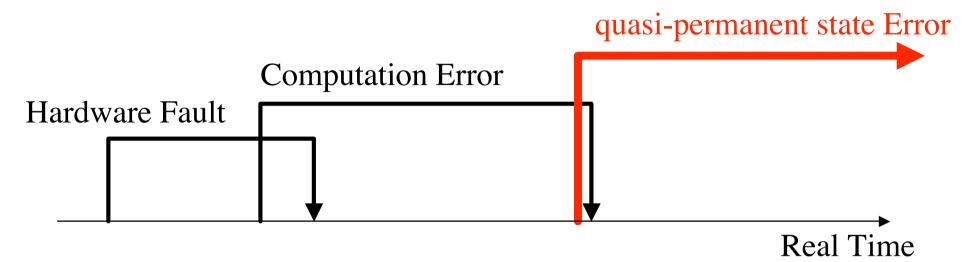
- Guardians are needed to avoid error propagation in the temporal domain
- ♦ Guardians must be fully independent: star coupler

Results are documented in the open literature

We observed the following *orders of magnitude* of *fail-silent* versus *non-fail-silent* failures of components:

Error Detection in	Ratio of fail-silent to	Experimental
the temporal domain	non-fail-silent failures	Evidence
No Error Detector	50:1	FI Measurements in PDCS Project
Local Guardian	1000: 1	Fault Injection FIT Project
Autonomous Central Guardian	no non-fail silent failure observed so far	Fault Injection in FIT/NEXT TTA

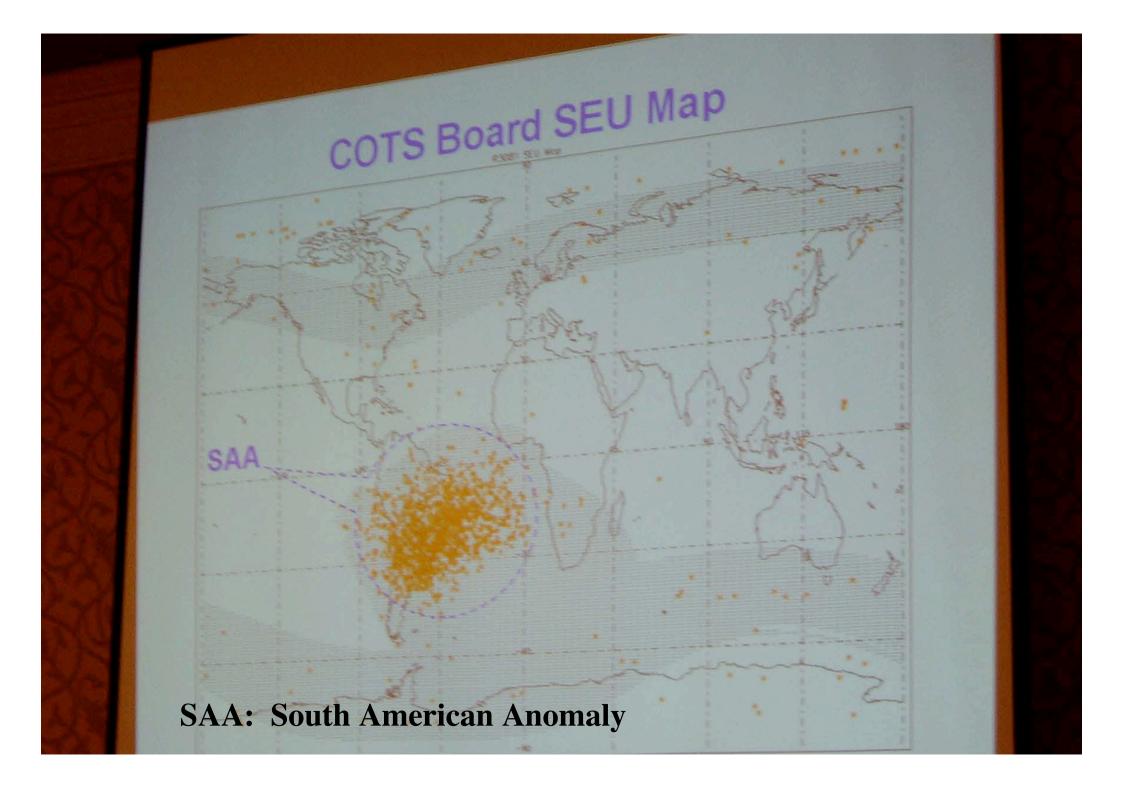
Transient Faults may cause Permanent State Errors²⁹



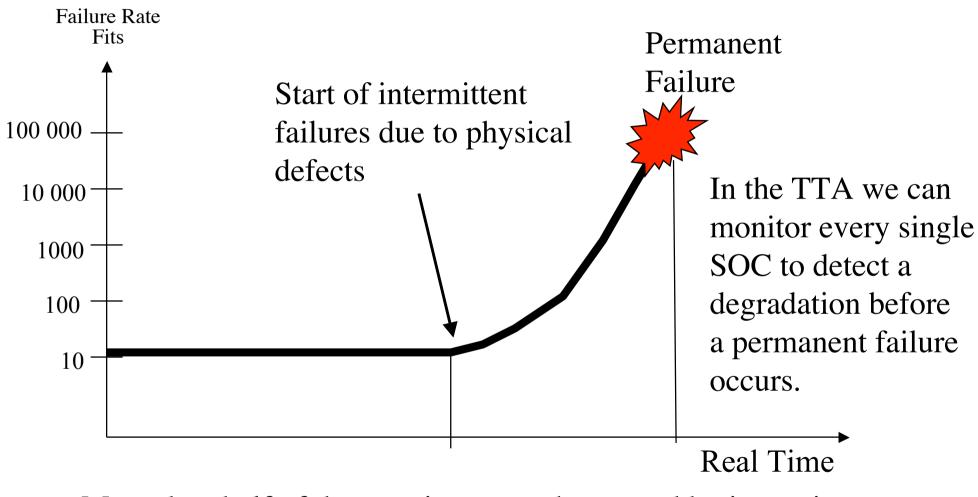
The interaction of a transient hardware fault with the state an cause a quasi-permanent state error: state erosion

Transient failures MTTF: 1000 hours Permanent failures MTTF: > 1 000 000 hours We have identified the following possible causes of a transient fault

- External Disturbances, e.g., high energy radiation (hardware)
- Internal Degradation of the chip hardware: e.g., corrosion of a PN junction (hardware)
- Heisenbugs, e.g., design error in the synchronization of processes (software)



Intermittent Failures of a Chip causes Transients



More than half of the transients may be caused by intermittents.

The Distinction between *Bohrbugs* and *Heisenbugs**

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- ◆ *Bohrbugs* are design errors in the software that cause reproducible failures. E.g., a logic error in a program.
- ♦ Heisenbugs are design errors in the software that seem to generate quasi-random failures. E.g., a synchronization error that will cause the occasional violation of an integrity condition.
- ♦ From a phenomenological point of view, a failure that is caused by a *Heisenbug* cannot be distinguished from a failure caused by transient hardware malfunction.
- Experience shows that it is much more difficult to find and eliminate the *Heisenbugs* than it is to eliminate the *Bohrbugs* from a large software system.

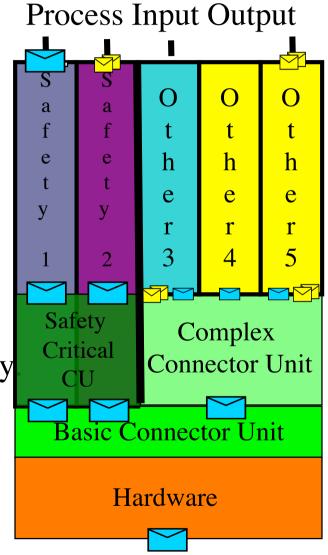
*J. Gray, "Why do Computers Stop and What can be done about it?," Proc. 5th Symp. on Reliability in Distributed Software and Database Systems, Los Angeles, CA, USA, 1986

- From the observation of a transient failure of a node, it *impossible* to identify in a *single function node* the cause of the transient.
- It is possible to reason about the cause of the transient if a *population of nodes* is observed over time.
- It is also possible to reason about the cause of the transient if the malfunctions of a *single multifunction* node are observed over time.

Mixed-Criticality TTA Node

Mixed-Criticality Node with 6 Partitions, controlled by connector units.

The two safety-critical partitions depend on the correctness of the Basic Connector Unit only







Critical Parts of a Mixed-Criticality TTA Node

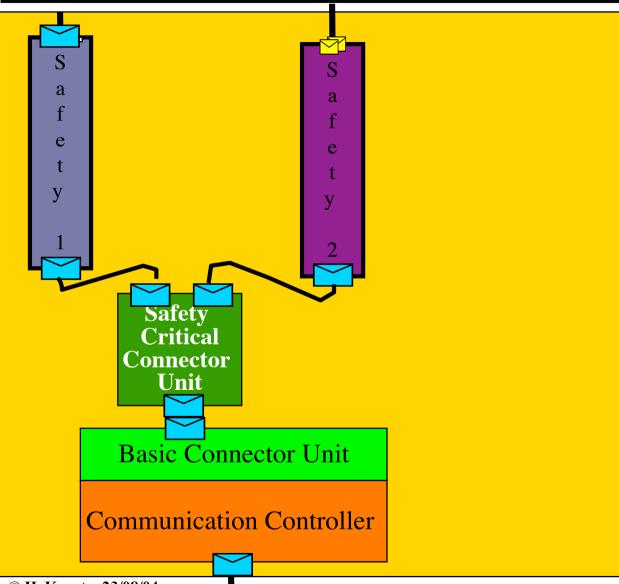
Process Input Output malign failures DAS 1 Safety Critical а a Safety Critical DAS 2 e e t y y benign failures 2 DAS 3 Safety Critical DAS 4 CU Basic Connector Unit Hardware

Mixed-Criticality Node with 6 Partitions, controlled by connector units.

The two safety-critical partitions depend on the correctness of the **Basic Connector Unit only** Minimize the complexity in the hardware and the software of the core servics of the TTA in order that they can be formally analyzed

- Partition the system such that modular certification is supported.
- Time-triggered (TT) communication with elementary interfaces--no backpressure
- ♦ Basic Connector Unit supports static mechanisms only
- Temporal encapsulation by design (hardware)
- Avoid algorithms which are not amenable to formal certification (e.g., feedback in the clock-synchronization)

Modular Certification of a TTA Node



Each unit can be certified in isolation form each other unit.

Unintended interactions are avoided by design.

Conclusion

- The Design of Safety-Critical Computing Systems requires a fault-tolerant architecture and a rigorous design methodology
- The precise specification of the fault hypothesis is the key document in the design of a fault-tolerant systems.
- The architecture of for a safety critical application must tolerate the arbitrary failure of any single VLSI Chip since we cannot assume that a chip contains two independent fault containment regions.